Docket No.

292853US2PCT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

GAU:

IN RE APPLICATION OF: Hendrikus Petrus VAN DER LAAK, et al.

SERIAL NO: New U.S PCT Application Based on PCT/NL04/00922

10. New 0.5 FC1 Application based on FC1/NL04/00922

FILED: FOR: Herewith EXAMINER:

METHOD, DEVICE AND DIFFRACTION GRATING FOR SEPARATING SEMICONDUCTOR ELEMENTS

FORMED ON A SUBSTRATE BY ALTERING SAID DIFFRACTION GRATING

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references cited in the International Search Report and listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- □ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number <u>15-0030</u>. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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IAP20 Rec'd PCT/PTO 29 JUN 2006

SHEET 1 OF 1

Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			292853US2PCT		SERIAL NO. Jew V.S. April 10 of 19 Based on PCT/NL04/00922		
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hendrikus Petrus VAN DER LAAK, et al.				
				FILING DATE		GROUP		
				Herewith				
				U.S. PATENT DOCUMENTS				
EXAMINER		DOCUMENT DATE		NAME CLASS		SUB FILING DATE		
INITIAL		NUMBER	_		05.00	CLASS IF APPROP		PPROPRIATE
	AA	6 635 849	10/21/03	OKAWA, Tatsuki et al.				
	AB	5 633 735	05/27/97	HUNTER, Robert O. Jr. et al.	 			
	AC	5 029 243	07/02/91	DAMMANN, Hans et al.				
	AD	5 922 224	07/13/99	BROEKROELOFS, Jan C.E.				
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		DOCUMENT NUMBER	DATE	COUNTRY	• . • •	TRANSLATION YES NO		
	AO	01/37769	05/31/01	wo				NO
	AP	0 679 469	11/02/95	EP(equivalent of US 6 008 914)				NO
	AQ	02/094528	11/28/02	WO(equivalent of US 2001/035401)	· • · · · · · · · · · · · · · · · · · ·			NO
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		OTHER R	EFERENCES (Including Author, Title, Date, Pertinen	t Pages, e	tc.)		
								
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Examiner					Date Considered			
*Examiner: In conformance	itial if r	eference is considered to considered. Include	I, whether or no	t citation is in conformance with MPEP 60 with next communication to applicant.	09; Draw li	ne through	citation	if not in